

Abstracts

On-Wafer Testing of MMIC with Monolithically Integrated Photoconductive Switches

S.L. Huang, E.A. Chauchard, C.H. Lee, T.T. Lee, H.-L.A. Hung and T. Joseph. "On-Wafer Testing of MMIC with Monolithically Integrated Photoconductive Switches." 1992 MTT-S International Microwave Symposium Digest 92.2 (1992 Vol. II [MWSYM]): 661-664.

This is the first report that photoconductive (PC) test structures have been fabricated monolithically with MMIC amplifiers for microwave characterization using a optical technique. Good agreement has been obtained between the measured results and those obtained from a conventional network analyzer.

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